

4V Drive Nch + Pch MOSFET

QS8M51

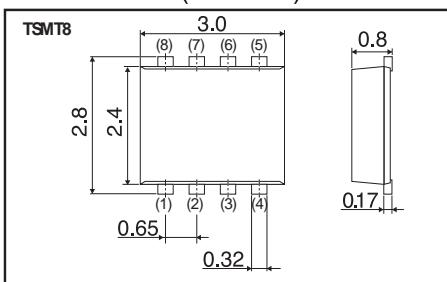
● Structure

Silicon N-channel MOSFET/
Silicon P-channel MOSFET

● Features

- 1) Low on-resistance.
- 2) Low voltage drive (4V drive).
- 3) Small surface mount package (TSMT8).

● Dimensions (Unit : mm)



Abbreviated symbol : M51

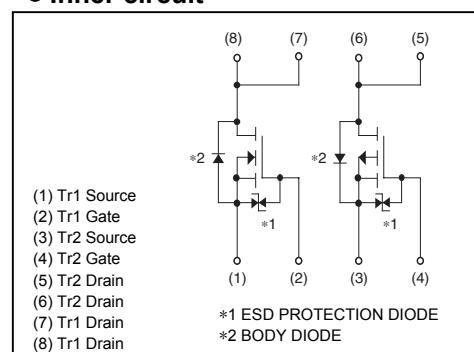
● Application

Switching

● Packaging specifications

Type	Package	Taping
	Code	TR
	Basic ordering unit (pieces)	3000
QS8M51	○	

● Inner circuit



(1) Tr1 Source
(2) Tr1 Gate
(3) Tr2 Source
(4) Tr2 Gate
(5) Tr2 Drain
(6) Tr2 Drain
(7) Tr1 Drain
(8) Tr1 Drain

*1 ESD PROTECTION DIODE
*2 BODY DIODE

● Absolute maximum ratings (Ta = 25°C)

Parameter	Symbol	Limits		Unit	
		Tr1 : N-ch	Tr2 : P-ch		
Drain-source voltage	V _{DSS}	100	-100	V	
Gate-source voltage	V _{GSS}	±20	±20	V	
Drain current	Continuous	I _D	±2	±1.5	A
	Pulsed	I _{DP}	*1 ±6	±6	A
Source current (Body Diode)	Continuous	I _s	1.0	-1.0	A
	Pulsed	I _{sp}	*1 6	-6	A
Power dissipation	P _D	*2 1.5		W / TOTAL	
		1.25		W / ELEMENT	
Channel temperature	T _{ch}	150		°C	
Range of storage temperature	T _{stg}	-55 to +150		°C	

*1 Pw≤10μs, Duty cycle≤1%

*2 Mounted on a ceramic board.

● Electrical characteristics (Ta = 25°C)

<Tr1(Nch)>

Parameter	Symbol	Min.	Typ.	Max.	Unit	Conditions
Gate-source leakage	I _{GSS}	-	-	±10	µA	V _{GS} =±20V, V _{DS} =0V
Drain-source breakdown voltage	V _{(BR)DSS}	100	-	-	V	I _D =1mA, V _{GS} =0V
Zero gate voltage drain current	I _{DSS}	-	-	1	µA	V _{DS} =100V, V _{GS} =0V
Gate threshold voltage	V _{GS(th)}	1	-	2.5	V	V _{DS} =10V, I _D =1mA
Static drain-source on-state resistance	R _{DS(on)} [*]	-	240	325	mΩ	I _D =2A, V _{GS} =10V
		-	250	340		I _D =2A, V _{GS} =4.5V
		-	260	355		I _D =2A, V _{GS} =4V
Forward transfer admittance	Y _{fs} [*]	1.9	-	-	S	V _{DS} =10V, I _D =2A
Input capacitance	C _{iss}	-	290	-	pF	V _{DS} =25V
Output capacitance	C _{oss}	-	30	-	pF	V _{GS} =0V
Reverse transfer capacitance	C _{rss}	-	20	-	pF	f=1MHz
Turn-on delay time	t _{d(on)} [*]	-	10	-	ns	V _{DD} =50V, I _D =1A
Rise time	t _r [*]	-	10	-	ns	V _{GS} =10V
Turn-off delay time	t _{d(off)} [*]	-	30	-	ns	R _L =50Ω, R _G =10Ω
Fall time	t _f [*]	-	15	-	ns	
Total gate charge	Q _g [*]	-	4.7	-	nC	V _{DD} =50V, I _D =2A
Gate-source charge	Q _{gs} [*]	-	1.2	-	nC	V _{GS} =5V
Gate-drain charge	Q _{gd} [*]	-	1.8	-	nC	

*Pulsed

● Body diode characteristics (Source-Drain)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Conditions
Forward Voltage	V _{SD} [*]	-	-	1.2	V	I _s =2A, V _{GS} =0V

*Pulsed

● Electrical characteristics (Ta = 25°C)

<Tr2(Pch)>

Parameter	Symbol	Min.	Typ.	Max.	Unit	Conditions
Gate-source leakage	I _{GSS}	-	-	±10	µA	V _{GS} =±20V, V _{DS} =0V
Drain-source breakdown voltage	V _{(BR)DSS}	-100	-	-	V	I _D =-1mA, V _{GS} =0V
Zero gate voltage drain current	I _{DSS}	-	-	-1	µA	V _{DS} =-100V, V _{GS} =0V
Gate threshold voltage	V _{GS(th)}	-1	-	-2.5	V	V _{DS} =-10V, I _D =-1mA
Static drain-source on-state resistance	R _{DS(on)} *	-	350	470	mΩ	I _D =-1.5A, V _{GS} =-10V
		-	380	510		I _D =-0.75A, V _{GS} =-4.5V
		-	400	540		I _D =-0.75A, V _{GS} =-4V
Forward transfer admittance	Y _{fs} *	1.5	-	-	S	V _{DS} =-10V, I _D =-1.5A
Input capacitance	C _{iss}	-	950	-	pF	V _{DS} =-25V
Output capacitance	C _{oss}	-	45	-	pF	V _{GS} =0V
Reverse transfer capacitance	C _{rss}	-	20	-	pF	f=1MHz
Turn-on delay time	t _{d(on)} *	-	10	-	ns	V _{DD} =-50V, I _D =-0.75A
Rise time	t _r *	-	15	-	ns	V _{GS} =-10V
Turn-off delay time	t _{d(off)} *	-	60	-	ns	R _L =66Ω, R _G =10Ω
Fall time	t _f *	-	10	-	ns	
Total gate charge	Q _g *	-	17	-	nC	V _{DD} =-50V, I _D =-1.5A
Gate-source charge	Q _{gs} *	-	4.5	-	nC	V _{GS} =-5V
Gate-drain charge	Q _{gd} *	-	5	-	nC	

*Pulsed

● Body diode characteristics (Source-Drain)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Conditions
Forward Voltage	V _{SD} *	-	-	-1.2	V	I _s =-0.75A, V _{GS} =0V

*Pulsed

●Electrical characteristic curves ($T_a=25^\circ\text{C}$)

⟨Tr.1(Nch)⟩

Fig.1 Typical Output Characteristics (I)

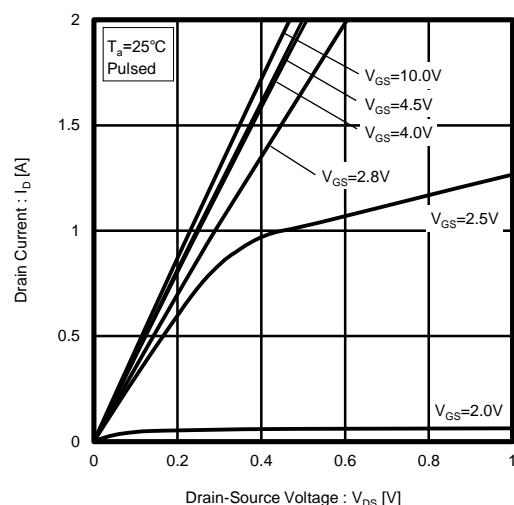


Fig.2 Typical Output Characteristics (II)

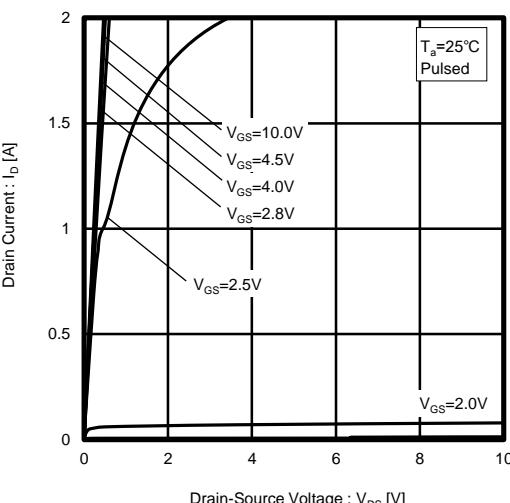


Fig.3 Static Drain-Source On-State Resistance vs. Drain Current

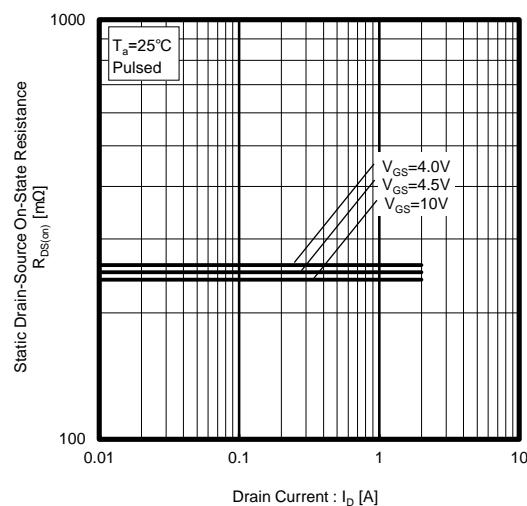


Fig.4 Static Drain-Source On-State Resistance vs. Drain Current

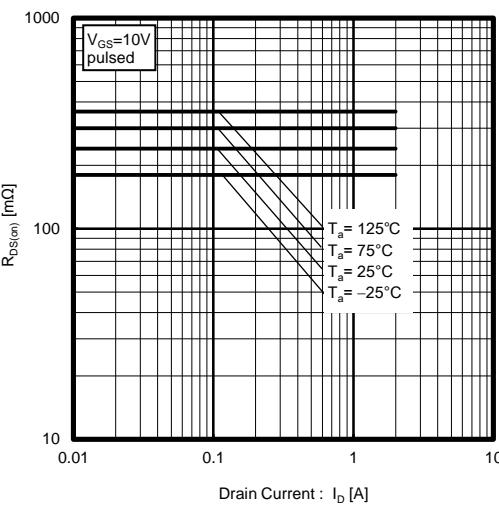


Fig.5 Static Drain-Source On-State Resistance vs. Drain Current

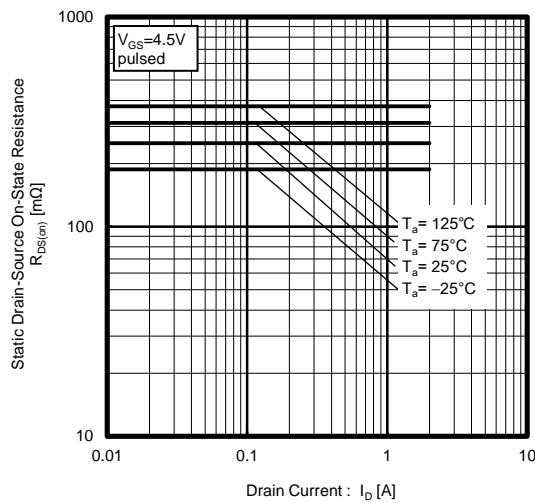


Fig.6 Static Drain-Source On-State Resistance vs. Drain Current

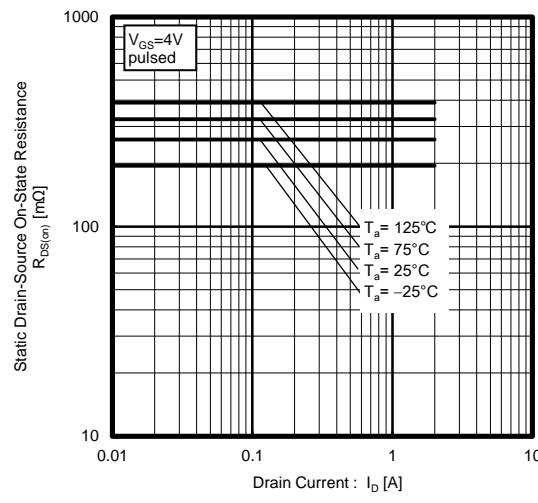


Fig.7 Forward Transfer Admittance vs. Drain Current

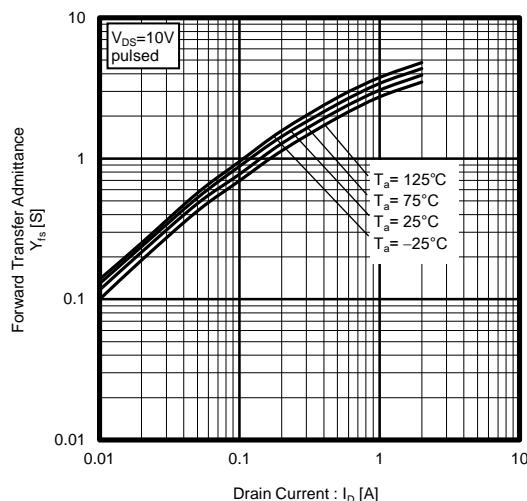


Fig.8 Typical Transfer Characteristics

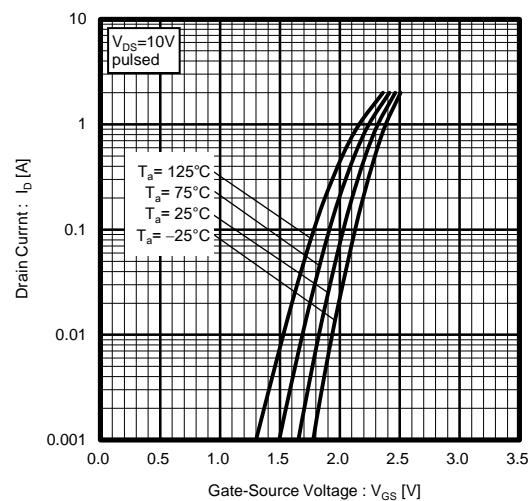


Fig.9 Source Current vs. Source-Drain Voltage

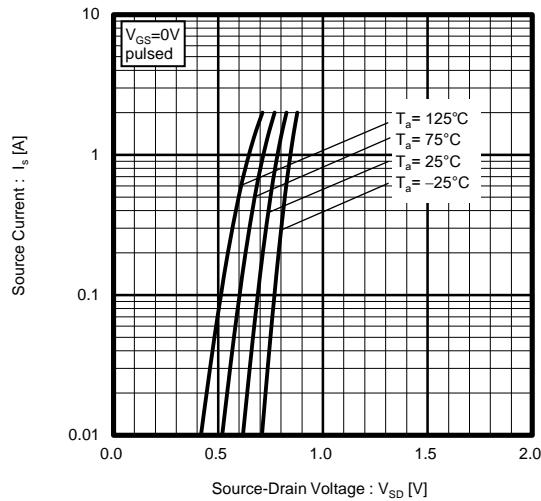


Fig.10 Static Drain-Source On-State Resistance vs. Gate-Source Voltage

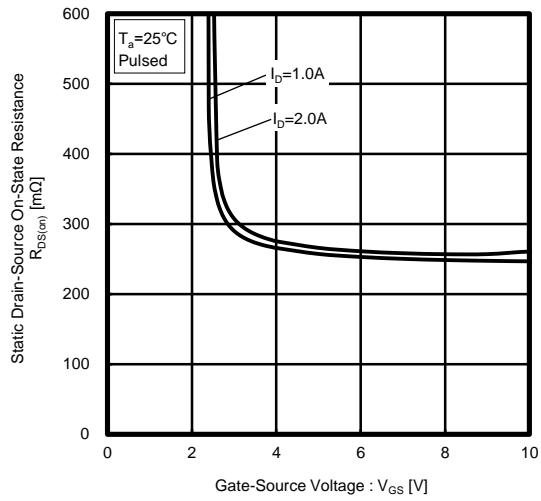


Fig.11 Switching Characteristics

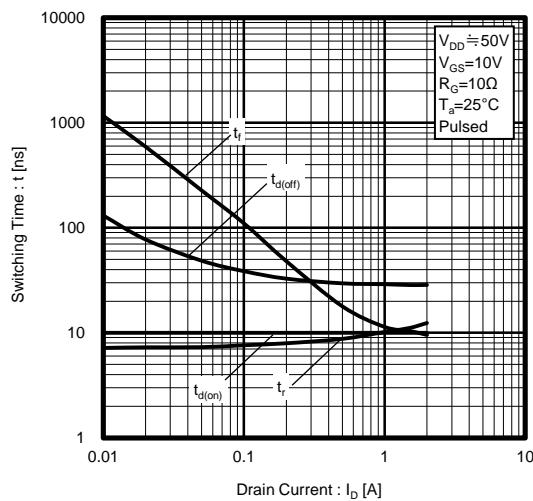


Fig.12 Dynamic Input Characteristics

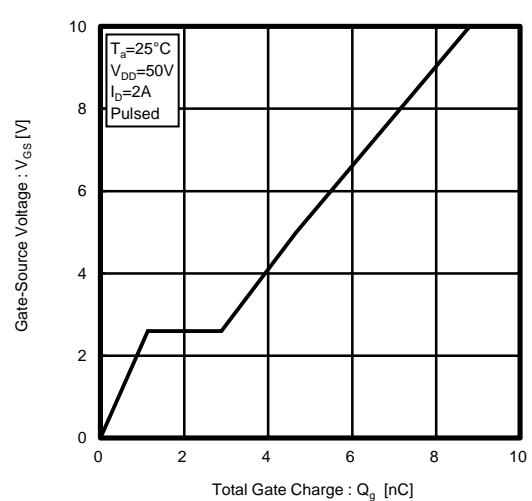


Fig.13 Typical Capacitance vs. Drain-Source Voltage

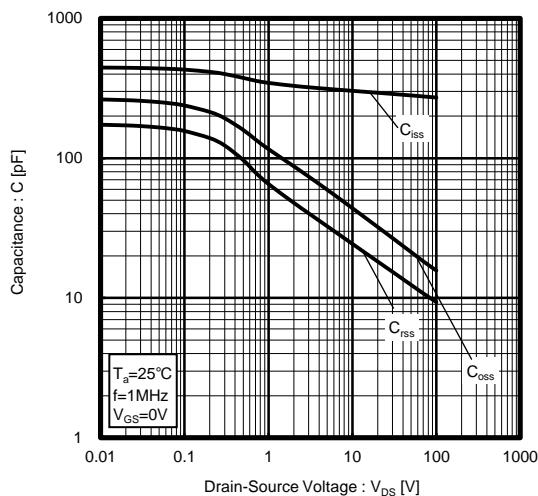


Fig.14 Normalized Transient Thermal Resistance v.s. Pulse Width

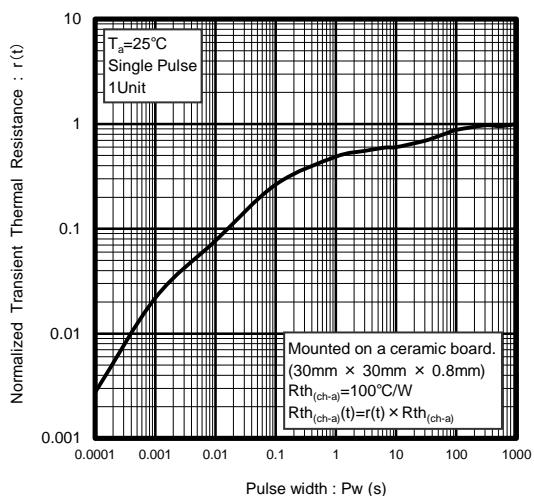
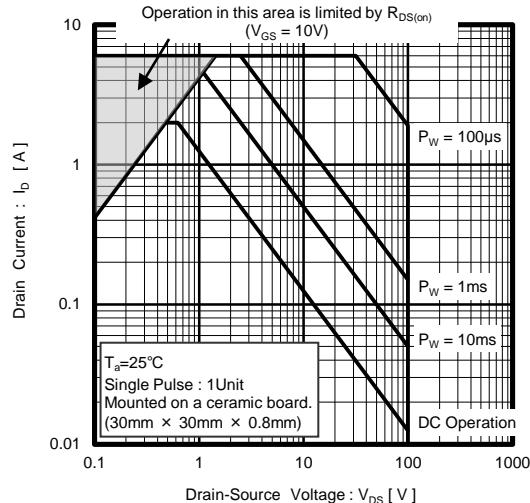


Fig.15 Maximum Safe Operating Area



$\langle \text{Tr.2(Pch)} \rangle$

Fig.1 Typical Output Characteristics (I)

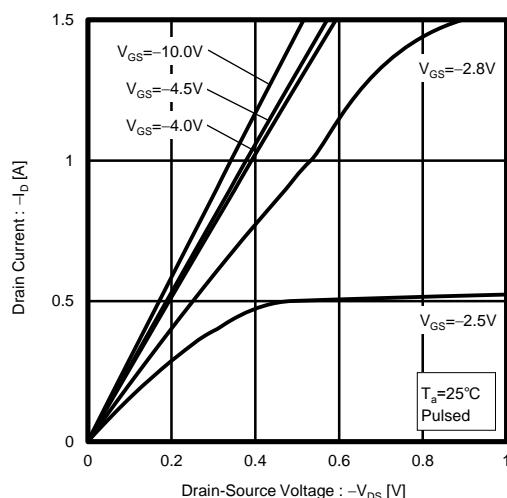


Fig.3 Static Drain-Source On-State Resistance vs. Drain Current

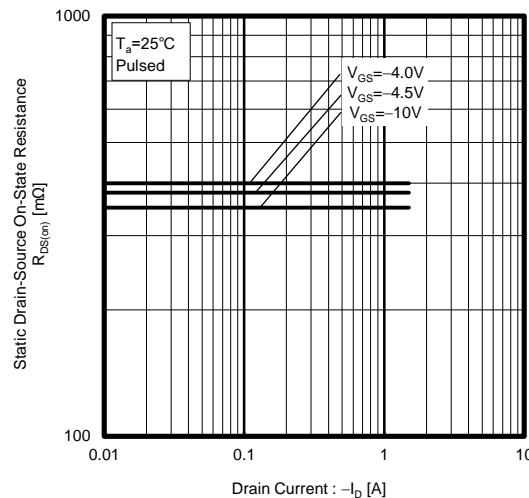


Fig.5 Static Drain-Source On-State Resistance vs. Drain Current

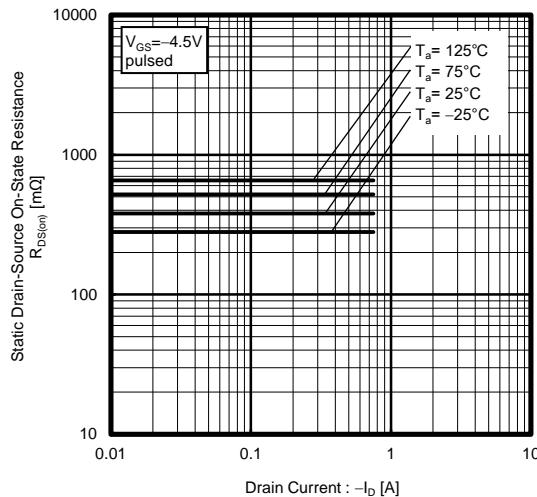


Fig.2 Typical Output Characteristics (II)

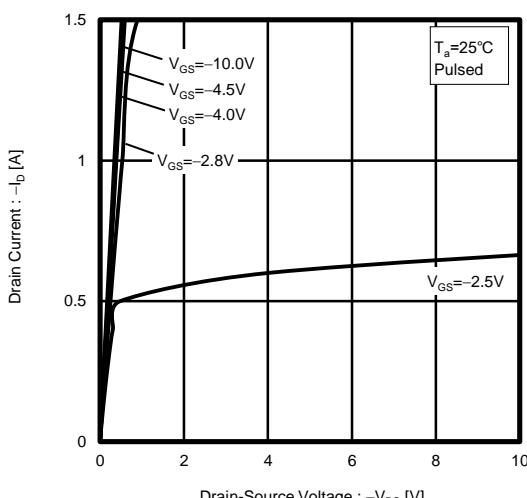


Fig.4 Static Drain-Source On-State Resistance vs. Drain Current

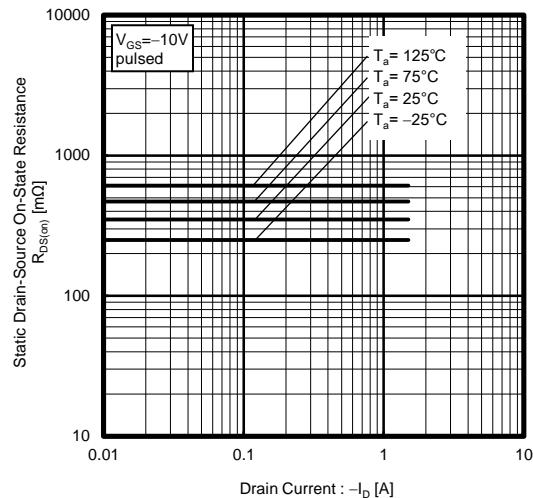


Fig.6 Static Drain-Source On-State Resistance vs. Drain Current

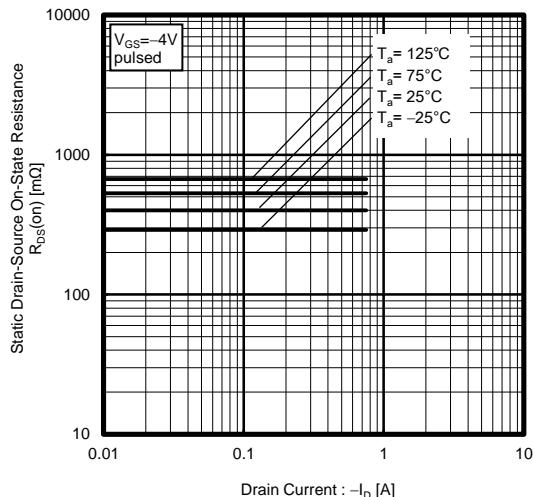


Fig.7 Forward Transfer Admittance vs. Drain Current

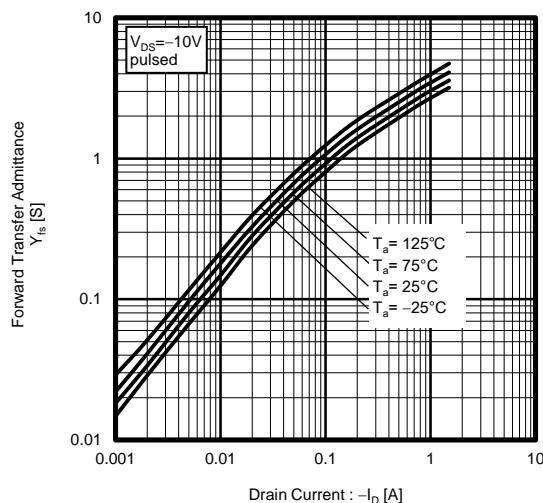


Fig.8 Typical Transfer Characteristics

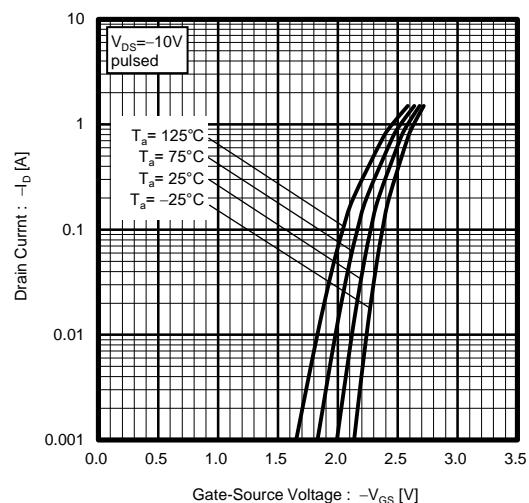


Fig.9 Source Current vs. Source-Drain Voltage

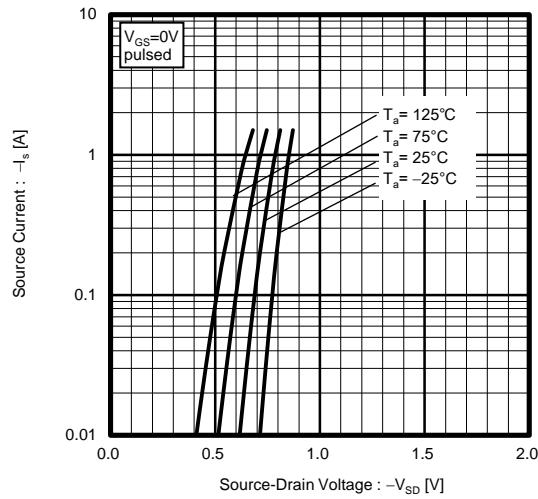


Fig.10 Static Drain-Source On-State Resistance vs. Gate-Source Voltage

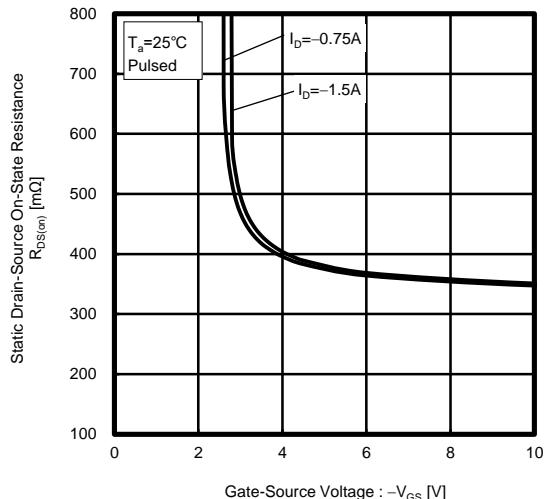


Fig.11 Switching Characteristics

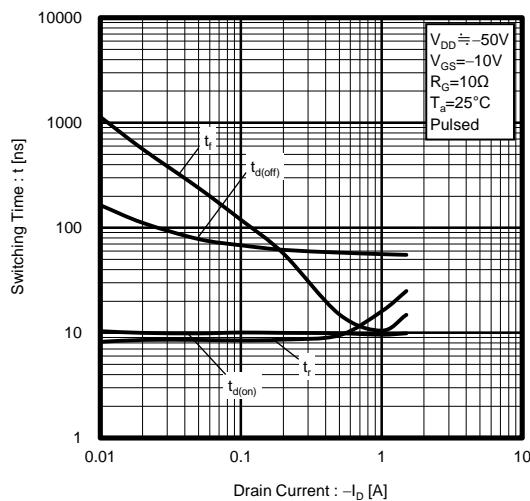


Fig.12 Dynamic Input Characteristics

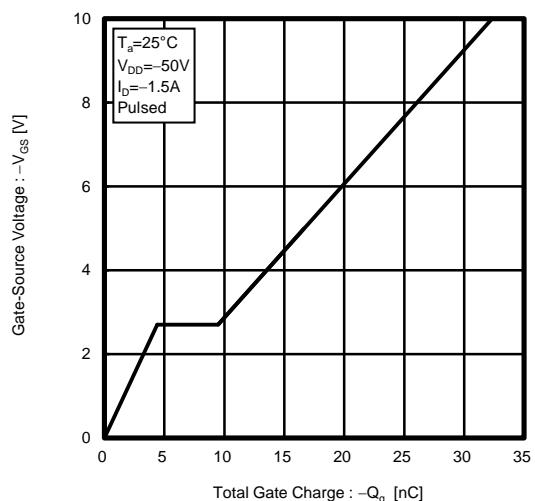


Fig.13 Typical Capacitance vs. Drain-Source Voltage

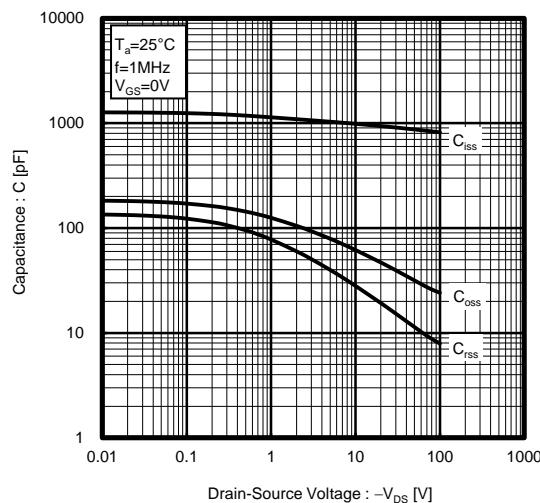


Fig.14 Normalized Transient Thermal Resistance v.s. Pulse Width

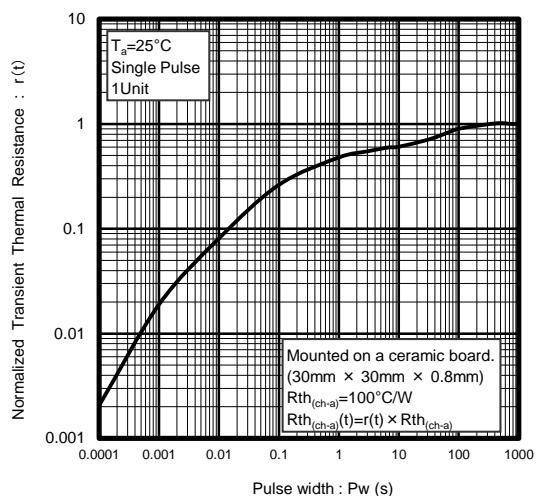
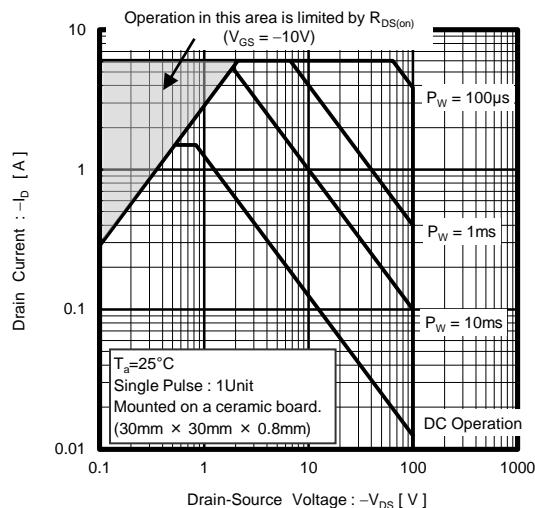


Fig.15 Maximum Safe Operating Area



● Measurement circuits

<Tr1(Nch)>

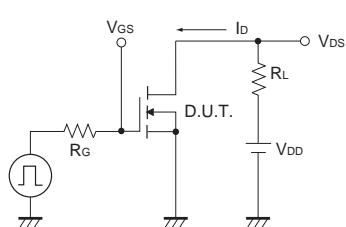


Fig.1-1 Switching Time Measurement Circuit

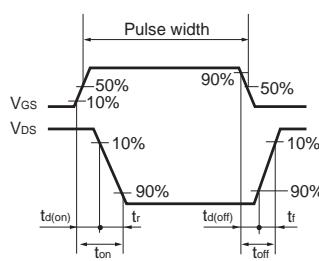


Fig.1-2 Switching Waveforms

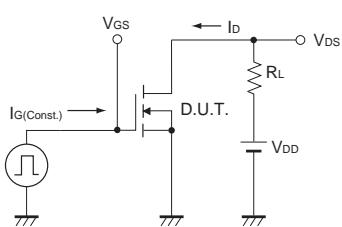


Fig.2-1 Gate Charge Measurement Circuit

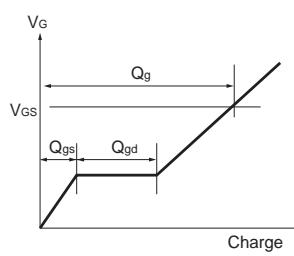


Fig.2-2 Gate Charge Waveform

<Tr2(Pch)>

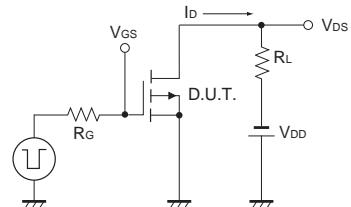


Fig.1-1 Switching Time Measurement Circuit

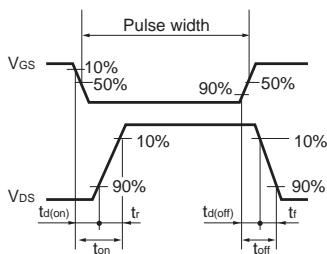


Fig.1-2 Switching Waveforms

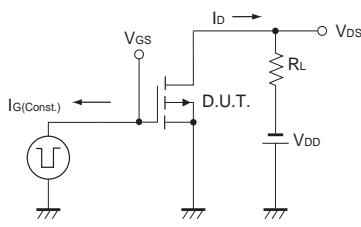


Fig.2-1 Gate Charge Measurement Circuit

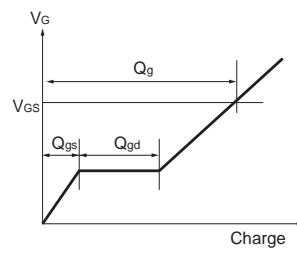


Fig.2-2 Gate Charge Waveform

Notes

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